

## Single P-Channel MOSFET

### ■ DESCRIPTION

SMC3207H is the P-Channel enhancement mode power field effect transistors, provide superior fast switching performance and withstand high energy pulse in the avalanche and commutation mode.

### ■ PART NUMBER INFORMATION

**SMC 3207 H - TR G**

a	b	c	d	e
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a : Company name.

b : Product Serial number.

c : Package code H:TO-252

d : Handling code TR:Tape&Reel

e : Green produce code G:RoHS Compliant

### ■ FEATURES

**$V_{DS}=-30V$ ,  $I_D=-69A$**

$R_{DS(ON)}=7m\Omega$ (Typ.)@ $V_{GS}=-10V$

$R_{DS(ON)}=10m\Omega$ (Typ.)@ $V_{GS}=-4.5V$

◆100% EAS Guaranteed

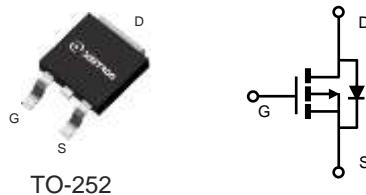
◆High power and current handling capability

### ■ APPLICATIONS

◆Load Switch

◆Power Applications

◆Portable Powered Systems



### ■ ABSOLUTE MAXIMUM RATINGS ( $T_A=25^\circ C$ Unless otherwise noted)

Symbol	Parameter	Rating	Units	
$V_{DSS}$	Drain-Source Voltage	-30	V	
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	V	
$I_D$	Continuous Drain Current	$T_c=25^\circ C$	-69	A
		$T_c=100^\circ C$	-43.5	A
$I_{DM}$	Pulsed Drain Current <sup>B</sup>		-276	A
$I_D$	Continuous Drain Current	$T_A=25^\circ C$	-21.8	A
		$T_A=70^\circ C$	-17.4	A
$P_D$	Power Dissipation <sup>A</sup>	$T_A=25^\circ C$	6.25	W
		$T_A=70^\circ C$	4	W
$I_{AS}$	Single Pulse Avalanche Current <sup>B</sup>		-40	A
$E_{AS}$	Single Pulse Avalanche energy L=0.1mH <sup>BE</sup>		80	mJ
$P_D$	Power Dissipation <sup>C</sup>	$T_c=25^\circ C$	62.5	W
		$T_c=100^\circ C$	25	W
$T_J$	Operation Junction Temperature		-55/150	°C
$T_{STG}$	Storage Temperature Range		-55/150	°C

### ■ THERMAL RESISTANCE

Symbol	Parameter	Typ	Max	Units
$R_{\theta JA}$	Thermal Resistance Junction to Ambient <sup>A</sup>	$t \leq 10s$	20	°C/W
	Thermal Resistance Junction to Ambient <sup>AC</sup>		50	
$R_{\theta JC}$	Thermal Resistance Junction to Case	Steady-State	2	

**ELECTRICAL CHARACTERISTICS( $T_A=25^\circ\text{C}$  Unless otherwise noted)**

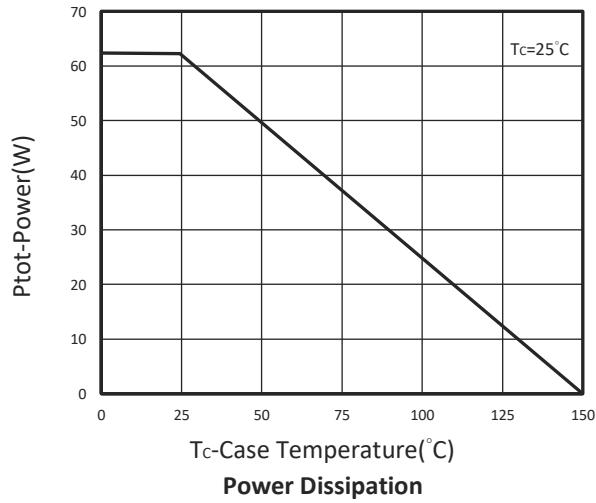
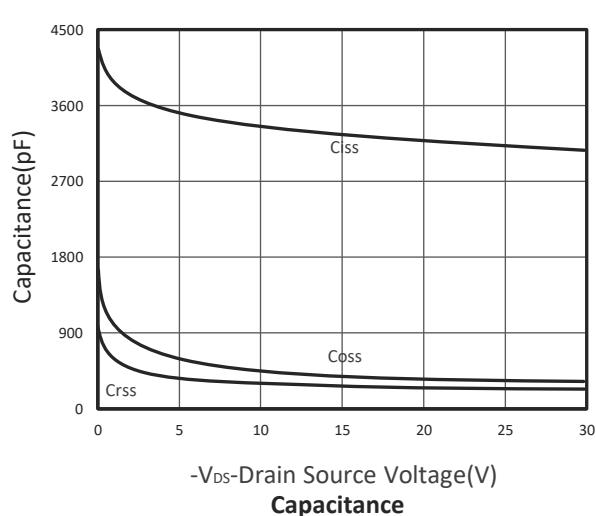
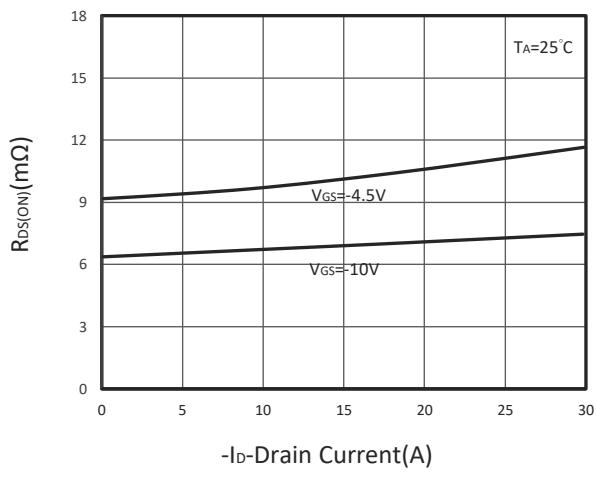
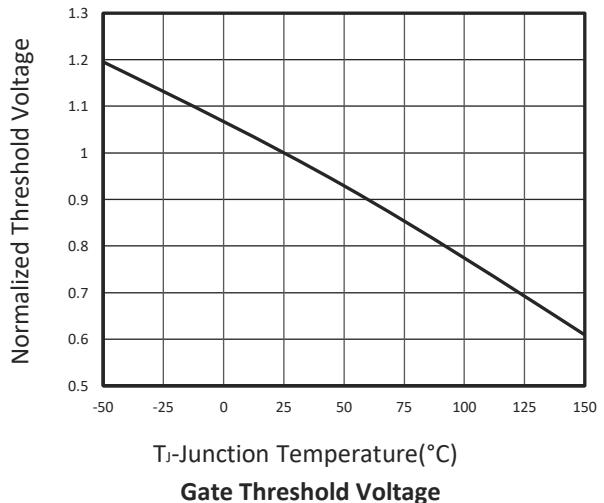
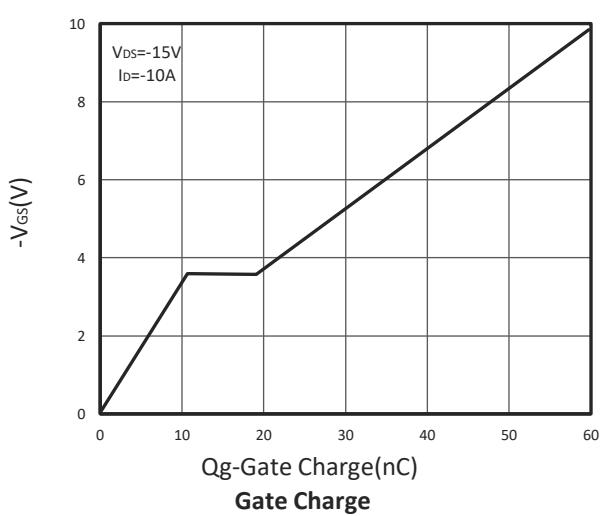
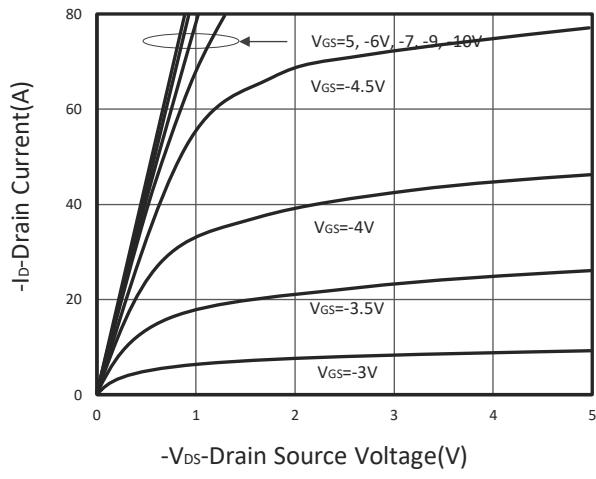
Symbol	Parameter	Condition	Min	Typ	Max	Unit	
<b>Static Parameters</b>							
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=-250\mu\text{A}$	-30			V	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	-1	-1.6	-2.5	V	
$I_{GSS}$	Gate Leakage Current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			$\pm100$	nA	
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}, T_J=25^\circ\text{C}$			-1	$\mu\text{A}$	
		$V_{DS}=-24\text{V}, V_{GS}=0\text{V}, T_J=75^\circ\text{C}$			-10		
$R_{DS(\text{ON})}$	Drain-source On-Resistance <sup>D</sup>	$V_{GS}=-10\text{V}, I_D=-20\text{A}$		7	8.5	$\text{m}\Omega$	
		$V_{GS}=-4.5\text{V}, I_D=-15\text{A}$		10	13		
$G_f$	Forward Transconductance	$V_{DS}=-10\text{V}, I_D=-10\text{A}$		14.8		S	
<b>Diode Characteristics</b>							
$V_{SD}$	Diode Forward Voltage <sup>D</sup>	$I_S=-1\text{A}, V_{GS}=0\text{V}$			-1	V	
$I_S$	Diode Continuous Forward Current				-69	A	
$t_{rr}$	Reverse Recovery Time	$I_S=-10\text{A}, dI/dt=100\text{A}/\mu\text{s}$		21		ns	
$Q_{rr}$	Reverse Recovery Charge			15.5		nC	
<b>Dynamic and Switching Parameters <sup>F</sup></b>							
$Q_g$	Total Gate Charge	$V_{DS}=-15\text{V}, V_{GS}=-10\text{V}, I_D=-10\text{A}$		61	85	nC	
$Q_g$	Total Gate Charge (4.5V)			30	42		
$Q_{gs}$	Gate-Source Charge			10.6	14.3		
$Q_{gd}$	Gate-Drain Charge			9	12.6		
$C_{iss}$	Input Capacitance	$V_{DS}=-15\text{V}, V_{GS}=0\text{V}, f=1\text{MHz}$		3230		pF	
$C_{oss}$	Output Capacitance			369			
$C_{rss}$	Reverse Transfer Capacitance			265			
$R_g$	Gate Resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		8.3		$\Omega$	
$t_{d(on)}$	Turn-On Time	$V_{DD}=-15\text{V}, V_{GS}=-10\text{V}, R_G=3\Omega$		24		nS	
$t_r$				11.6			
$t_{d(off)}$	Turn-Off Time			78.8			
$t_f$				33.8			

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged.

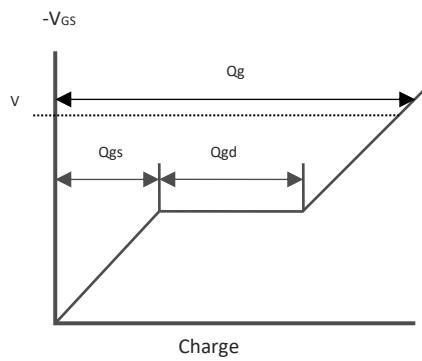
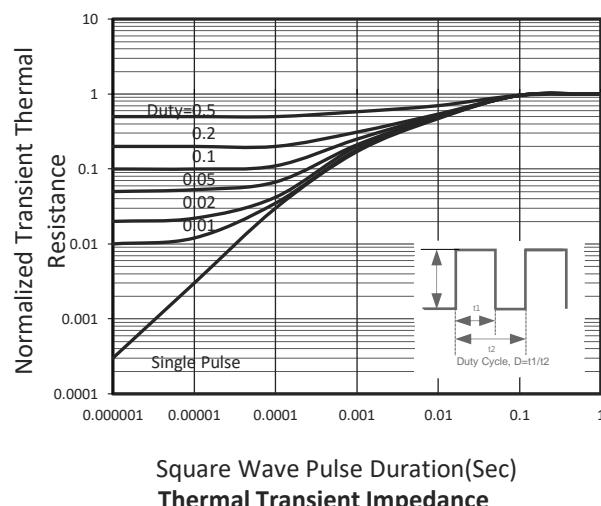
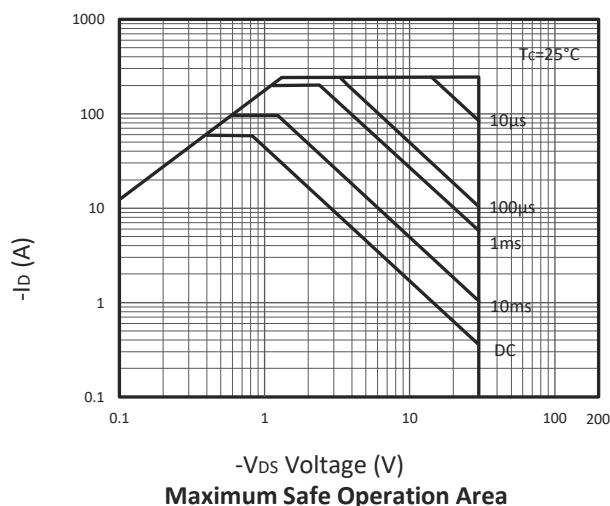
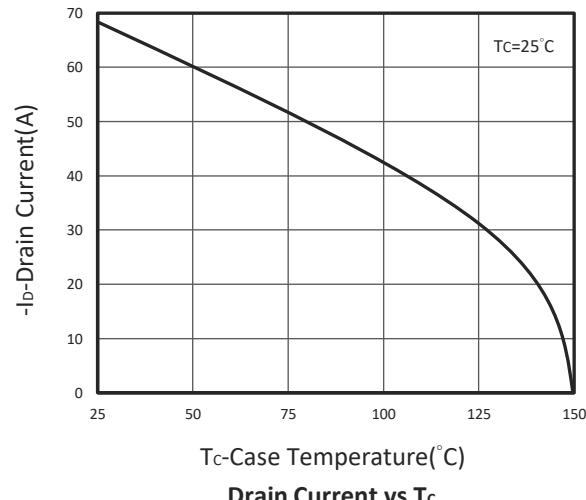
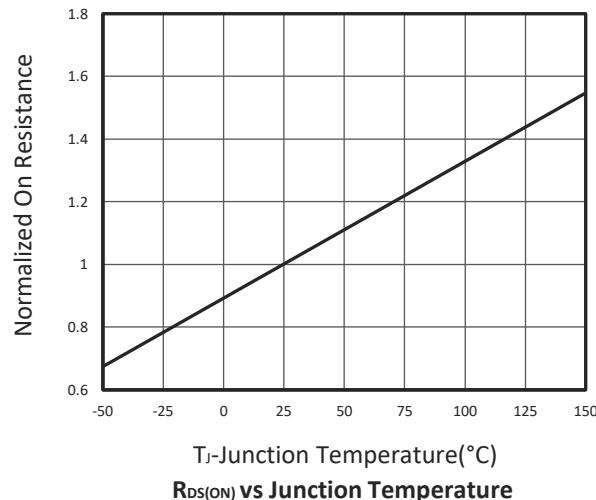
- A. Surface mounted on FR4 board using 1 in<sup>2</sup> pad size.
- B. Pulsed width limited by maximum junction temperature,  $T_J(\text{MAX})=150^\circ\text{C}$  (initial temperature  $T_J=25^\circ\text{C}$ ).
- C. Using  $\leq 10\text{s}$  junction-to-ambient thermal resistance is base on  $T_J(\text{MAX})=150^\circ\text{C}$ .
- D. Pulse test width  $\leq 300\mu\text{s}$  and duty cycle  $\leq 2\%$ .
- E. The EAS data shows maximum, The test condition is  $V_{DD}=-25\text{V}, V_{GS}=-10\text{V}, L=0.1\text{mH}, I_{AS}=-40\text{A}$
- F. Guaranteed by design, not subject to production testing.

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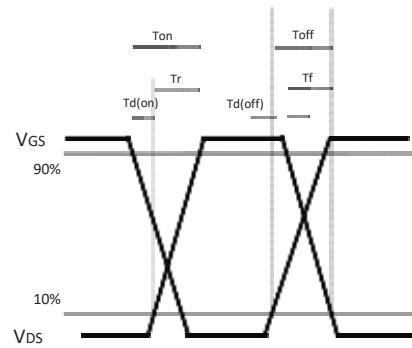
## TYPICAL CHARACTERISTICS



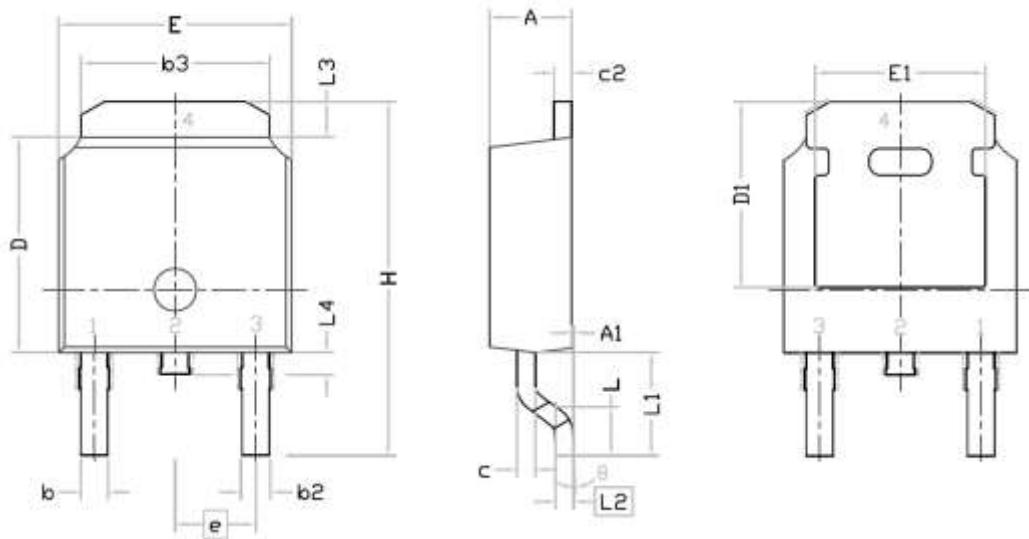
## TYPICAL CHARACTERISTICS



**Gate Charge Waveform**



**Switching Time Waveform**

**■ TO-252 PACKAGE DIMENSIONS**


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.380	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.640	0.880	0.025	0.035
b2	0.770	1.140	0.030	0.045
b3	5.210	5.460	0.205	0.215
c	0.460	0.600	0.018	0.024
c2	0.460	0.580	0.018	0.023
D	6.000	6.223	0.236	0.245
D1	5.210	-	0.205	-
E	6.400	6.731	0.252	0.265
E1	4.400	-	0.173	-
e	2.286 BSC.		0.090 BSC.	
H	9.400	10.40	0.370	0.409
L	1.400	1.770	0.055	0.070
L1	2.743 REF.		0.108 REF.	
L2	0.508 BSC.		0.020 BSC.	
L3	0.890	1.270	0.035	0.050
L4	0.640	1.010	0.025	0.040
Θ	0°	10°	0°	10°

Recommended Land Pattern

